

IGBT3 Chip

Features:

- 1200V Trench & Field Stop technology
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

This chip is used for:

• power modules



drives



Chip Type	V _{CE}	I c	Die Size	Package
SIGC20T120LE	1200V	15A	4.41 x 4.47 mm ²	sawn on foil

Mechanical Parameters

Wechanical Parameters			
Raster size	4.41 x 4.47		
Emitter pad size	2.901 x 2.995	mm ²	
Gate pad size	1.107 x 0.702		
Area total	19.71		
Thickness	120	μm	
Wafer size	200	mm	
Max.possible chips per wafer	1381		
Passivation frontside	Photoimide		
Pad metal	3200 nm AlSiCu		
Backside metal	Ni Ag –system suitable for epoxy and soft solder die bonding		
Die bond	Electrically conductive glue or solder		
Wire bond	Al, <500μm		
Reject ink dot size	Ø 0.65mm ; max 1.2mm		
Recommended storage environment	Store in original container, in dry nitrogen, in dark environment, < 6 month at an ambient temperature of 23°C		



Maximum Ratings

Parameter	Symbol	Value	Unit	
Collector-Emitter voltage, T_{vj} =25 °C	V _{CE}	1200	V	
DC collector current, limited by $T_{\rm vjmax}$	I _C	1)	Α	
Pulsed collector current, $t_{\rm p}$ limited by $T_{\rm vjmax}$	I _{c,puls}	45	Α	
Gate emitter voltage	V _{GE}	±20	V	
Junction temperature range	T_{vj}	-55 +175	°C	
Operating junction temperature	T _{vj}	-55+150	°C	
Short circuit data 2) V_{GE} = 15V, V_{CC} = 900V, T_{vj} = 125°C	tsc	10	μs	
Reverse bias safe operating area ² (RBSOA)	$I_{C,max} = 30A, V_{CE,max} = 1200V$ $T_{vj} \le 125^{\circ}C$			

¹⁾ depending on thermal properties of assembly

Static Characteristic (tested on wafer), T_{vj} =25 °C

Parameter	Symbol	Conditions	Value			Unit
Tarameter	Cymbol	Conditions	min.	typ.	max.	
Collector-Emitter breakdown voltage	V _{(BR)CES}	$V_{\rm GE}$ =0V , $I_{\rm C}$ = 0.5mA	1200			
Collector-Emitter saturation voltage	V _{CEsat}	V _{GE} =15V, I _C =15A	1.4	1.7	2.1	V
Gate-Emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =0.6mA , $V_{\rm GE}$ = $V_{\rm CE}$	5.0	5.8	6.5	
Zero gate voltage collector current	I _{CES}	V _{CE} =1200V , V _{GE} =0V			2.16	μΑ
Gate-Emitter leakage current	I _{GES}	V_{CE} =0V , V_{GE} =20V			120	nA
Integrated gate resistor	$r_{\rm G}$			none		Ω

Dynamic Characteristic (not subject to production test - verified by design / characterization), T_{v_j} =25 °C

Parameter	Symbol	Conditions	Value			Unit
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Input capacitance	Cies	V_{CE} =25V, V_{GE} =0V, f=1MHz		1100		pF
Reverse transfer capacitance	C _{res}			50		

²⁾ not subject to production test - verified by design/characterization

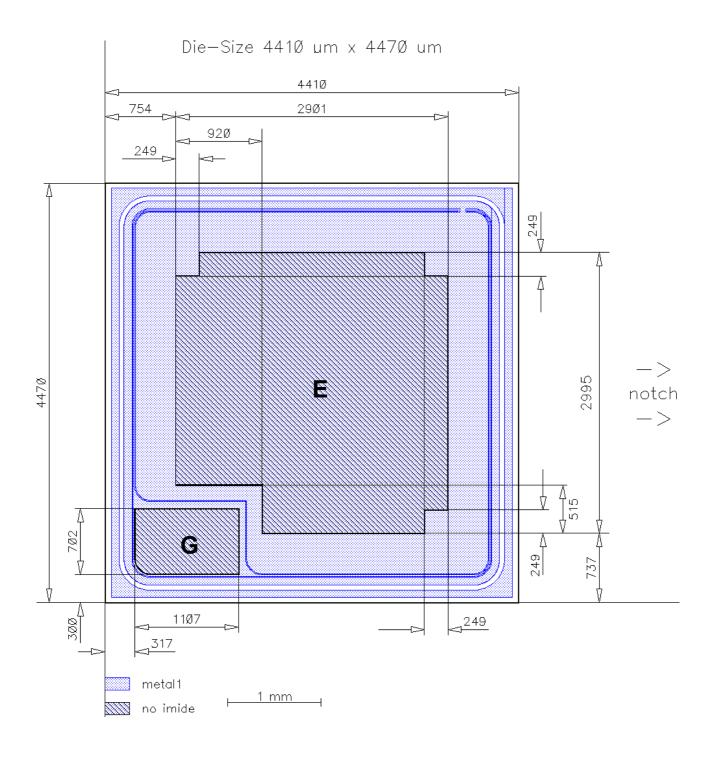


Further Electrical Characteristic

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.



Chip Drawing



E = Emitter

G = Gate



Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Version	Subjects (major changes since last revision)	Date
2.0	Release of final datasheet, change wafer size to 200 mm	30.04.2010

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